



YEA SHIN TECHNOLOGY CO., LTD

YS60N04R

N-Channel Enhancement MOSFET

VDS= 60V, ID= 45A



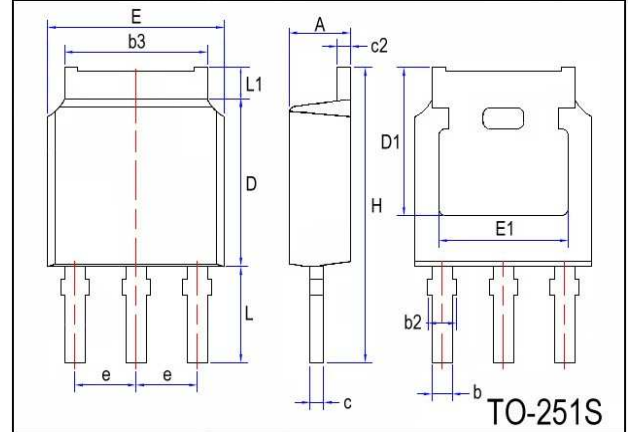
DESCRIPTION

The YS60N04R uses advanced Trench technology and designs to provide excellent $R_{DS(ON)}$ with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications.

The YS60N04R meet the RoHS and Green Product requirement, 100% EAS and Rg guaranteed with full function reliability approved.

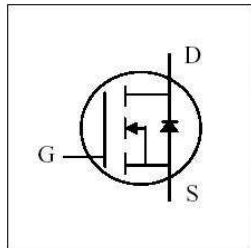
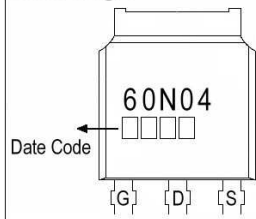
FEATURES

- Low On-Resistance
- Low Input Capacitance
- Green Device Available
- Low Miller Charge
- 100% EAS Guaranteed



REF.	Millimeter			REF.	Millimeter		
	Min.	Nom.	Max.		Min.	Nom.	Max.
A	2.20	2.30	2.38	D1	5.10	-	-
b	0.64	-	0.88	E	6.40	6.60	6.73
b2	0.72	-	1.14	E1	4.40	-	-
b3	5.13	5.33	5.46	e	2.286 BSC		
c	0.40	0.50	0.60	H	10.40	-	11.45
c2	0.40	-	0.60	L	3.30	-	4.30
D	6.00	6.10	6.22	L1	0.90	-	1.25

Marking :



Absolute Maximum Ratings

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V _{DS}	60	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current ¹	I _D @T _C =25°C	45	A
	I _D @T _C =100°C	29	A
Pulsed Drain Current ²	I _{DM} @T _C =25°C	180	A
Total Power Dissipation ⁴	P _D @T _C =25°C	63	W
	P _D @T _A =25°C	2.5	W
Single Pulse Avalanche Energy, L=0.1mH ³	E _{AS}	61	mJ
Single Pulse Avalanche Current, L=0.1mH ³	I _{AS}	35	A
Operating Junction and Storage Temperature Range	T _J , T _{STG}	-55 ~ +150	°C

Thermal Data

Parameter	Symbol	Conditions	Max. Value	Unit
Thermal Resistance Junction-ambient ¹	R _{θJA}	Steady State	50	°C/W
Thermal Resistance Junction-case ¹	R _{θJC}	Steady State	2.0	°C/W

DEVICE CHARACTERISTICS

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Electrical Characteristics (T_j = 25°C unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	BV _{DSS}	60	-	-	V	V _{GS} =0, I _D =250uA
Gate Threshold Voltage	V _{GS(th)}	1.0	1.7	2.5	V	V _{DS} =V _{GS} , I _D =250uA
Gate-Source Leakage Current	I _{GSS}	-	-	±100	nA	V _{GS} = ±20V
Drain-Source Leakage Current(T _j =25°C)	I _{DSS}	-	-	1	uA	V _{DS} =60V, V _{GS} =0
Drain-Source Leakage Current(T _j =125°C)		-	-	10	uA	V _{DS} =48V, V _{GS} =0
Static Drain-Source On-Resistance ²	R _{DS(ON)}	-	10.5	12	mΩ	V _{GS} =10V, I _D =30A
		-	12	15		V _{GS} =4.5V, I _D =15A
Total Gate Charge ²	Q _g	-	39.2	-	nC	I _D =10A V _{DS} =30V V _{GS} =10V
Gate-Source Charge	Q _{gs}	-	5.9	-		
Gate-Drain ("Miller") Charge	Q _{gd}	-	8.8	-		
Turn-on Delay Time ²	T _{d(on)}	-	9.6	-	ns	V _{DS} =15V I _D =10A V _{GS} =10V R _G =6Ω
Rise Time	T _r	-	28.2	-		
Turn-off Delay Time	T _{d(off)}	-	45.3	-		
Fall Time	T _f	-	10.9	-		
Input Capacitance	C _{iss}	-	2100	-	pF	V _{GS} =0V V _{DS} =25V f=1.0MHz
Output Capacitance	C _{oss}	-	165	-		
Reverse Transfer Capacitance	C _{rss}	-	80	-		
Gate Resistance	R _g	-	1.6	3.2	Ω	f=1.0MHz

Guaranteed Avalanche Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Single Pulse Avalanche Energy ⁵	EAS	33.8	-	-	mJ	V _{DD} =25V, L=0.1mH, I _{AS} =26A

Source-Drain Diode

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Diode Forward Voltage ²	V _{SD}	-	-	1.2	V	I _S =10A, V _{GS} =0V, T _J =25°C
Continuous Source Current ^{1,6}	I _S	-	-	45	A	V _G =V _D =0V, Force Current
Pulsed Source Current ^{2,6}	I _{SM}	-	-	180	A	

Notes: 1. The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.

2. The data tested by pulsed, pulse width ≤ 300us, duty cycle ≤ 2%.

3. The EAS data shows Max. rating. The test condition is V_{DD}=25V, V_{GS}=10V, L=0.1mH, I_{AS}=35A.

4. The power dissipation is limited by 150°C junction temperature.

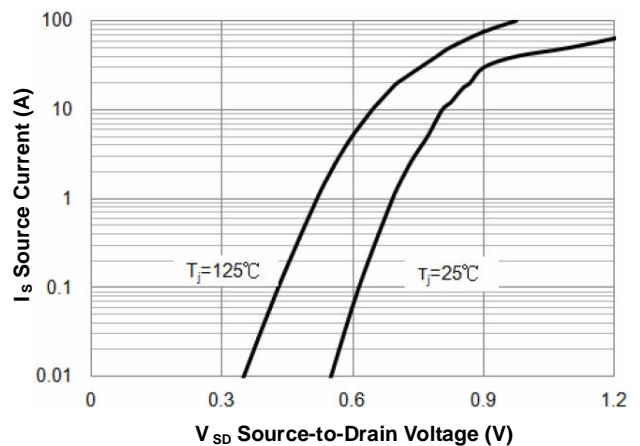
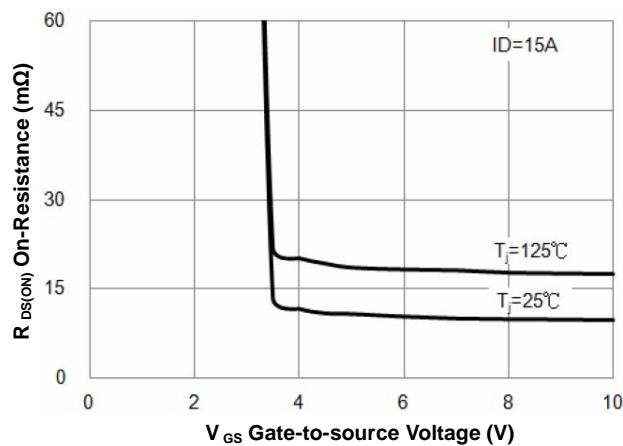
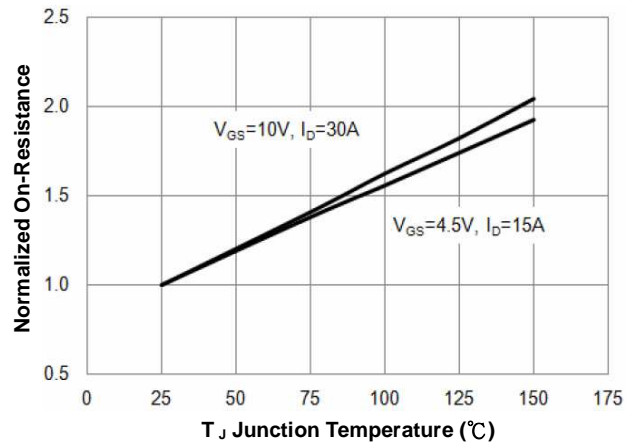
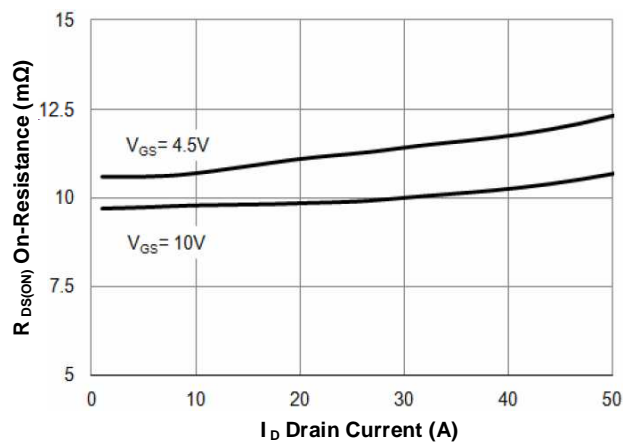
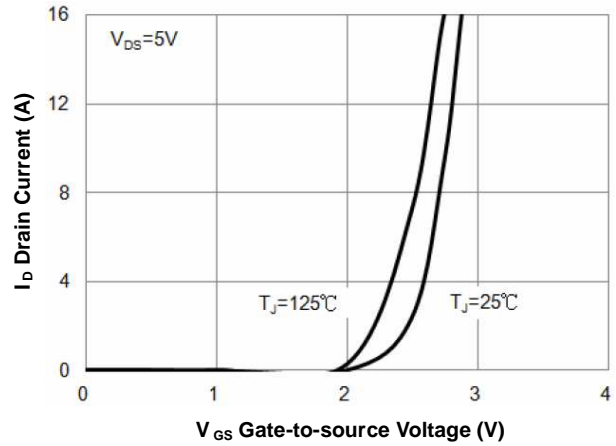
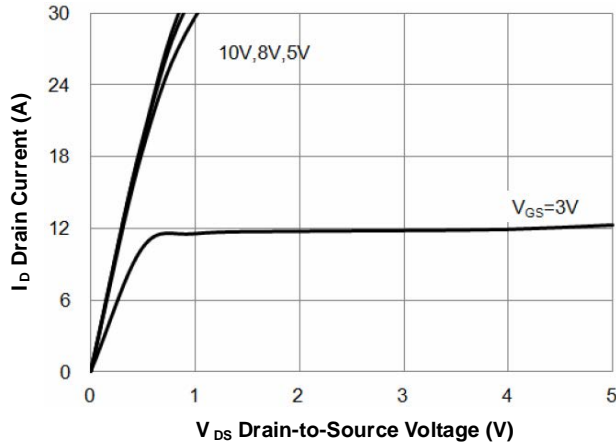
5. The Min. value is 100% EAS tested guarantee.

6. The data is theoretically the same as I_D and I_{DM}, in real applications, should be limited by total power dissipation.

DEVICE CHARACTERISTICS

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Typical Characteristics



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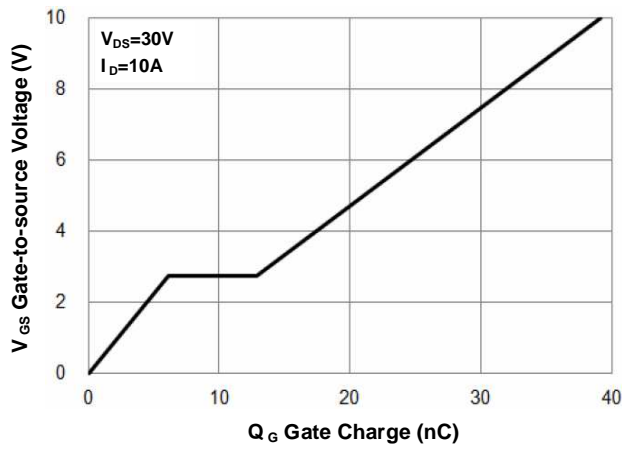


Fig.7 Gate Charge Characteristics

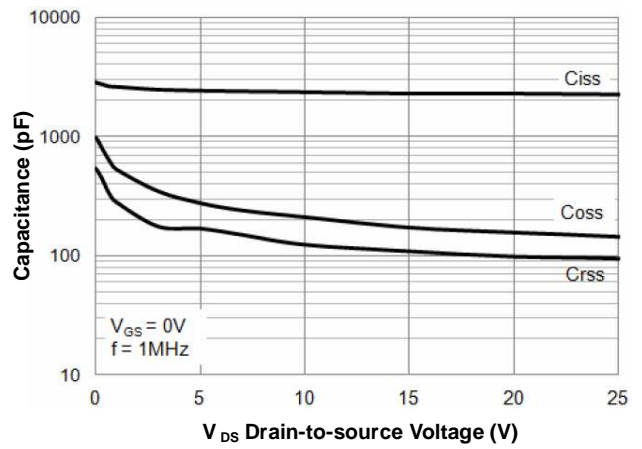


Fig.8 Capacitance Characteristics

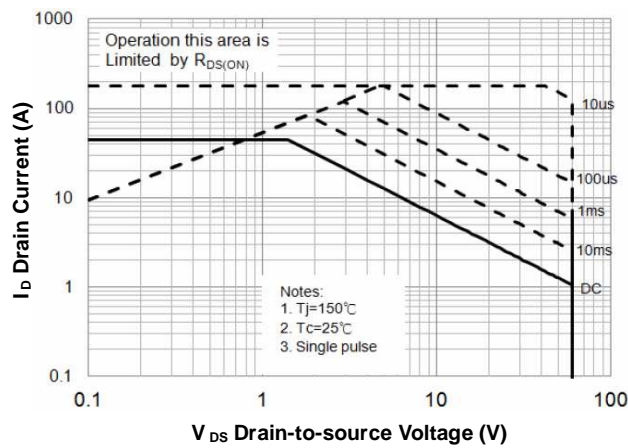


Fig.9 Safe Operating Area

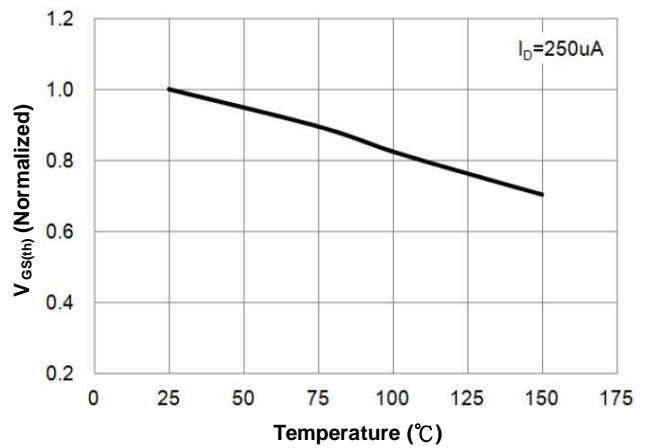


Fig.10 Normalized $V_{GS(th)}$ vs. Temperature

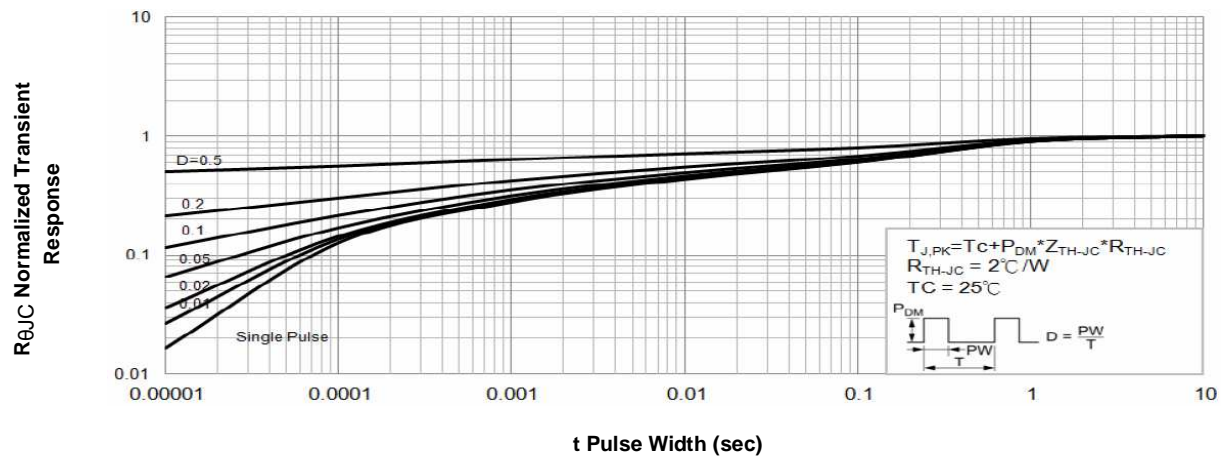


Fig.11 Normalized Maximum Transient Thermal Impedance